

CONTRIBUTION FROM THE DEPARTMENT OF CHEMISTRY, FORDHAM UNIVERSITY, NEW YORK, NEW YORK 10458,  
AND RCA LABORATORIES, PRINCETON, NEW JERSEY 08540**Crystal Structure of Iridium Trisilicide, IrSi<sub>3</sub>**

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Small single crystals of IrSi<sub>3</sub> were obtained from a polycrystalline sample that had been prepared by induction heating of the elements. The crystals are hexagonal, space group  $P6_3mc$  with  $a = 4.351 \pm 0.001 \text{ \AA}$ ,  $c = 6.622 \pm 0.002 \text{ \AA}$ , and  $Z = 2$ . The structure is an unusual one, consisting of infinite, planar, four-connected layers of silicon atoms perpendicular to the  $c$  axis, with each iridium atom spaced at unequal distances between two silicon layers. The iridium atoms each make nine almost equal contacts with silicon atoms. The silicon-silicon distances of  $2.175 \text{ \AA}$  within each layer are distinctly shorter than the silicon-silicon elemental single bond distance.

During a study of the system iridium-silicon, we have prepared single crystals of composition IrSi<sub>3</sub>. This phase has been made previously in polycrystalline form, and its crystal system and unit cell dimensions have been deduced.<sup>1-3</sup> In the present work the crystal structure has been determined from single-crystal X-ray data.

**Experimental Section**

**Preparation and Physical Measurements.**—Stoichiometric quantities of very coarse powders of iridium (>99.5%) and silicon (99.99%) were placed in an alumina boat and melted by induction heating (3 MHz) under an argon atmosphere. The compound was cooled slowly and although the polycrystalline sample adhered to the boat, small single-crystal fragments could be obtained. Rectangular polycrystalline samples were cut for electrical resistivity measurements; the room-temperature resistivity was  $5 \times 10^{-4} \text{ ohm cm}$  and at  $500^\circ$  it was about  $7 \times 10^{-4} \text{ ohm cm}$ .

**X-Ray Measurements and Crystal Data.**—The crystals were found to be hexagonal with Laue symmetry  $6/mmm$  from  $hkl$  and  $hkl$  equinclination Weissenberg photographs ( $\lambda 1.5405 \text{ \AA}$ ,  $25^\circ$ ). Accurate cell dimensions were obtained by a least-squares fit of back-reflection lines of the powder pattern, giving  $a = 4.351 \pm 0.001 \text{ \AA}$ ,  $c = 6.622 \pm 0.002 \text{ \AA}$ . These cell constants and the details of the pattern itself agreed well with the previously published data.<sup>2</sup> The density calculated for two formula weights per unit cell is  $8.455 \text{ g cm}^{-3}$  compared to the reported value<sup>3</sup> of  $8.64 \text{ g cm}^{-3}$ . Systematic absences in the single-crystal Weissenberg data were  $hhl$  with  $l$  odd, indicating one of the three space groups  $P6_3mc$ ,  $P6_2c$ , or  $P6_3/mmc$ .

For intensity measurements a very small crystal, almost cubic in shape and  $0.025 \text{ mm}$  on edge, was used. The reciprocal lattice layers  $0kl$ ,  $1kl$ ,  $2kl$ , and  $hhl$  were recorded using an equinclination Weissenberg camera and Ni-filtered Cu K $\alpha$  radiation. The multiple-film technique was used and intensities were estimated visually by comparison with a time-calibrated intensity strip. The separate layers were brought to a common scale by least-squares fit of the common reflections. Of 57 independent, nonzero reflections three were measured on three layers, forty on two layers, and the rest on only one layer. In view of the high absorption of the crystals ( $\mu = 1298 \text{ cm}^{-1}$ ) accurate absorption corrections were made using a modified Busing-Levy program.<sup>4</sup>

**Structure Determination and Refinement.**—The three-dimensional Patterson function showed an outstanding peak at  $1/3, 2/3, 1/2$  corresponding to a vector between iridium atoms in the special positions  $1/3, 2/3, 1/4; 2/3, 1/3, 3/4$  of the space groups  $P6_2c$  and  $P6_3/mmc$  or the (b) positions  $1/3, 2/3, z; 2/3, 1/3, 1/2 + z$  of the space group  $P6_3mc$ . Since this space group has no unique origin in the  $z$  direction, the  $z$  parameter could be taken as  $1/4$ . The only other two independent peaks of any height in the Patterson map were at  $1/2, 1/2, 0.177$  and  $1/6, 5/6, 0.323$ . These two peaks were almost identical in height after normalizing for the different Patterson symmetries of the positions and were 23% of the

normalized Ir-Ir peak. These peaks corresponded very well to vectors between the iridium atoms and silicon atoms in the (c) positions of the space group  $P6_3mc$ :  $x, \bar{x}, z; x, 2x, z; 2\bar{x}, \bar{x}, z; \bar{x}, x, 1/2 + z; \bar{x}, 2\bar{x}, 1/2 + z; 2x, x, 1/2 + z$  with  $x = 5/6$  and  $z = 0.073$ .

Using these coordinates, the structure was refined first by difference Fourier methods and then by full-matrix least squares, using a modified Busing-Martin-Levy program.<sup>5</sup> Three cycles of isotropic refinement converged to a conventional  $R = 0.075$  and  $wR = 0.095$ . The isotropic  $B$  values were  $1.53 (12)$  for Ir and  $4.95 (67)$  for Si. Three further cycles using anisotropic temperature parameters for Ir and isotropic for Si gave  $R = 0.072$  and  $wR = 0.092$ .

The corresponding observed and calculated structure factors are given in Table I, and the refined structural parameters, in

TABLE I  
OBSERVED AND CALCULATED STRUCTURE FACTORS FOR IrSi<sub>3</sub><sup>a</sup>

hkl	F <sub>o</sub>	F <sub>c</sub>	hkl	F <sub>o</sub>	F <sub>c</sub>	hkl	F <sub>o</sub>	F <sub>c</sub>	hkl	F <sub>o</sub>	F <sub>c</sub>	hkl	F <sub>o</sub>	F <sub>c</sub>
000	--	228.6	107	43.9	41.8	204	32.0	29.4	304	55.4	53.8	401	42.7	42.8
002	99.1	200.7	108	20.5	20.1	207	38.1	38.1	306	28.2	27.7	402	19.7	20.6
004	80.1	84.1	110	95.7	90.2	210	34.2	33.5	310	66.5	68.0	403	26.4	25.7
006	72.3	77.1	112	103.3	100.4	211	62.5	63.9	312	31.5	48.0	404	40.4	18.4
008	36.0	39.2	114	84.8	78.4	212	40.3	40.8	314	47.6	43.2	310	18.5	21.7
100	56.9	59.3	116	55.2	50.5	213	85.9	59.2	316	28.3	27.0	311	32.8	34.0
101	88.5	98.9	200	58.3	64.6	214	36.8	31.2	318	46.9	45.3	312	18.0	18.6
102	54.3	57.0	201	88.0	94.9	215	50.4	43.1	320	27.6	25.7	313	41.2	33.4
103	113.2	97.4	202	35.6	36.3	216	19.7	19.5	322	44.2	43.3	410	34.5	36.8
104	42.5	42.8	203	55.4	47.9	217	31.8	31.2	324	20.9	21.6	412	37.9	36.6
105	80.2	58.0	204	33.3	32.5	300	58.1	61.1	326	22.2	22.2			
106	28.7	29.2	205	65.2	59.3	302	63.2	67.2	400	25.0	27.0			

<sup>a</sup> Cu K $\alpha$  radiation; F<sub>c</sub> for contents of one unit cell.TABLE II  
STRUCTURAL PARAMETERS WITH STANDARD DEVIATIONS FOR IrSi<sub>3</sub><sup>a</sup>

Parameter	Ir	Si
$x$	$1/3$	$0.818 (12)$
$y$	$2/3$	$0.182$
$z$	$1/4$	$0.083 (5)$
$\beta(1,1)$	$0.0497 (48)$	$5.14 (73)^b$
$\beta(2,2)$	$0.0497$	
$\beta(3,3)$	$0.0075 (9)$	
$\beta(1,2)$	$0.0249$	
$\beta(1,3)$	$0.0$	
$\beta(2,3)$	$0.0$	

<sup>a</sup> Temperature factor for Ir is of the form  $\exp[-(\beta_{11}h^2 + \beta_{22}k^2 + \beta_{33}l^2 + 2\beta_{12}hk + 2\beta_{13}hl + 2\beta_{23}kl)]$ . <sup>b</sup> Value of  $B (\text{\AA}^2)$  in the temperature factor  $\exp[-(B \sin^2 \theta)/\lambda^2]$ .

Table II. According to Hamilton's test<sup>6</sup> the latter values of  $R$  and  $wR$  are significant at the 10% level. However, anisotropic refinement for the silicon atoms in addition brought no significant improvement. Since only one set of  $F_{hkl}$ ,  $F_{\bar{h}\bar{k}\bar{l}}$  were estimated, an attempt was made to distinguish these by refining both enantiomorphs of the noncentrosymmetric structure using the real and imaginary parts of the anomalous dispersion corrections.<sup>7</sup> The differences in the calculated structure factors were so small that both  $R$  and  $wR$  were identical in both refinements and the coordinates listed are arbitrarily assigned to correspond

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(1) J. H. Buddery and A. J. E. Welch, *Nature (London)*, **167**, 362 (1951).(2) S. Bhan and K. Schubert, *Z. Metallk.*, **51**, 327 (1960).(3) L. N. Finnie, *J. Less-Common Metals*, **4**, 24 (1962).(4) W. R. Busing and H. A. Levy, *Acta Crystallogr.*, **10**, 180 (1957).

(5) W. R. Busing, K. O. Martin, and H. A. Levy, "A Fortran Crystallographic Least-Squares Program," Report TM-305, Oak Ridge National Laboratory, Oak Ridge, Tenn., 1962.

(6) W. C. Hamilton, *Acta Crystallogr.*, **18**, 502 (1965).(7) C. H. Dauben and D. H. Templeton, *ibid.*, **8**, 842 (1955).

to  $F_{hk}$ . All refinements were on the basis of  $F$ . An empirical weighting scheme was derived by plotting  $\Delta F$  vs.  $F$  and in final refinement  $\sigma F_o = 1.20 + 0.052F_o$ . The form factors used are those given in ref 8. The thermal ellipsoids found for the iridium atoms are restricted by symmetry so that the axes within the  $ab$  plane are equal, and the short, unique axis is parallel to  $c$ . The axial ratio is 0.59.

### Results and Discussion

The crystal structure of  $\text{IrSi}_3$  is illustrated in Figure 1. The silicon atoms are arranged in infinite planar

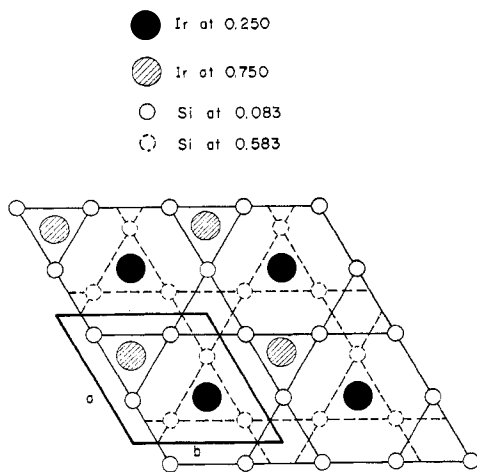


Figure 1.—Positions of the atoms in  $\text{IrSi}_3$ . The  $z$  coordinates (height above the plane of the diagram) are given in fractions of the  $c$  axis.

layers perpendicular to the  $c$  axis, with two such layers per unit cell. These layers are of the four-connected planar net type consisting of one-third hexagons and two-thirds triangles,<sup>9</sup> which is well known in alloy structures, e.g.,  $\text{CaCu}_5$ .<sup>10</sup> In addition to having four

(8) "International Tables for X-Ray Crystallography," Vol. III, Kynoch Press, Birmingham, England, 1962, pp 202–204.

(9) A. F. Wells, "Structural Inorganic Chemistry," Clarendon Press, Oxford, 1962, p 103.

(10) H. Haucke, *Z. Anorg. Allg. Chem.*, **244**, 17 (1940).

near neighbors within the layer, each silicon atom is in contact with three iridium atoms, two on one side and one on the other side of the layer. Each iridium atom, between two silicon layers, is in contact with nine silicon atoms. Of these, six form a hexagon in the nearer layer with  $\text{Ir-Si} = 2.44 \pm 0.05 \text{ \AA}$  while three are in a triangle in the further layer with  $\text{Ir-Si} = 2.49 \pm 0.04 \text{ \AA}$ .

For the "ideal" value,  $\frac{5}{6}$ , for the silicon parameter all the close silicon-silicon distances would be equal. Taking the refined  $x$  value these distances would fall into two groups, with the distances in triangles in contact with iridium atoms being  $1.98 \pm 0.16 \text{ \AA}$  and the others  $2.37 \pm 0.16 \text{ \AA}$ . However the differences between the two sets is less than  $3\sigma$  and may not be real. Regardless of the exact value of  $x$  it is clear that the Si-Si distances must average  $a/2$  or  $2.175 \pm 0.001 \text{ \AA}$  which is considerably shorter than the elemental single-bond distance of  $2.3516 \pm 0.0001 \text{ \AA}$  for silicon.<sup>11</sup> In order to explain the higher observed bond order in  $\text{IrSi}_3$  it is necessary to postulate electron transfer from the iridium atoms to the silicon layers. The  $60^\circ$  angles at each silicon atom would seem to favor a resonating structure giving partial double-bond character to essentially equal bonds rather than a nonresonating structure with bonds of appreciably different character.

The structure here described for  $\text{IrSi}_3$  has identical iridium positions but quite different silicon positions from the structure proposed by Finnie<sup>3</sup> on the basis of powder data. He noted good agreement between the powder patterns of  $\text{IrSi}_3$  and  $\text{HgMg}_3$  ( $\text{Na}_3\text{As}$  type). However this agreement is due to domination of the X-ray intensities by the heavy atom in both cases. The three-dimensional Patterson map derived from the single-crystal data is quite incompatible with a structure similar to that of  $\text{Na}_3\text{As}$  and can only be interpreted by a structure containing planar networks of silicon atoms.

(11) A. Smakula and J. Kalnajs, *Phys. Rev.*, **99**, 1737 (1955).

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## A New Isomer of Diidotetraphosphorus Trisulfide. The Preparation and Crystal Structure of $\beta\text{-P}_4\text{S}_3\text{I}_2$ <sup>1</sup>

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$\beta\text{-P}_4\text{S}_3\text{I}_2$  is prepared by the reaction of  $\text{P}_4\text{S}_3$  with  $\text{I}_2$  in solution. The structure was determined from three-dimensional X-ray data collected by standard Weissenberg multiple-film techniques and refined with a data set collected by counter methods using Mo radiation. The compound crystallizes in the orthorhombic space group  $Pnma$  with  $a = 9.399 (2) \text{ \AA}$ ,  $b = 16.343 (4) \text{ \AA}$ ,  $c = 6.657 (9) \text{ \AA}$ , and four molecules per unit cell. The structure was refined with 259 observed reflections to a conventional residual of  $R = 0.037$ . The molecules lie on a crystallographic mirror plane, with one sulfur and two phosphorus atoms on the mirror. The P-S bond lengths range from 2.091 (16) to 2.145 (10)  $\text{ \AA}$ , the P-P bond length is 2.221 (10)  $\text{ \AA}$ , and the P-I bond length is 2.471 (8)  $\text{ \AA}$ . Evidence is presented to support the reaction sequence  $\text{P}_4\text{S}_3 + \text{I}_2 \rightarrow \beta\text{-P}_4\text{S}_3\text{I}_2 \rightarrow \alpha\text{-P}_4\text{S}_3\text{I}_2$ , where  $\alpha\text{-P}_4\text{S}_3\text{I}_2$  is a previously reported  $\text{P}_4\text{S}_3\text{I}_2$  structure which has a P-S framework different from that of  $\beta\text{-P}_4\text{S}_3\text{I}_2$ .

### Introduction

The phosphorus sulfides ( $\text{P}_4\text{S}_n$ ,  $n = 3, 5, 7, 9, 10$ ) constitute a series of molecules with cagelike structures

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unique in inorganic stereochemistry.<sup>2,3</sup> The compound  $\text{P}_4\text{S}_3\text{I}_2$  is closely related to this series, and the

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